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In re Application of:

Brian S. Beaman

Atty. Docket: YOR919990088US1

Brian S. Beaman et al.

Art Unit: 2829

Serial No.: 09/251,988

Examiner: Jermele M. Hollington

Filed: February 17, 1999

For: Title STRUCTURAL DESIGN AND PROCESSES TO CONTROL PROBE
POSITION ACCURACY IN A WAFER TEST PROBE ASSEMBLY

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

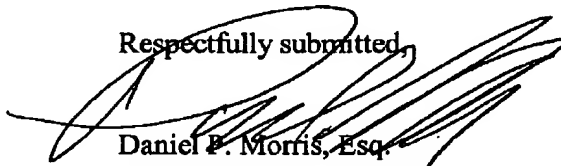
Attached is an Information Disclosure Statement and Notice of Citation of references of relating copending U.S. Application No.: 10/928,473, filed August 27, 2004.

The listing of these materials is not to be construed as an admission that such is actually prior art with respect to the invention of the present application and is not to be construed that such is material with respect to the present invention.

Since these documents are being submitted with an Request for Continued Examination request, applicants believe no fee is due.

Please charge any fee necessary to enter this paper and any previous paper to deposit account 09-0468.

Respectfully submitted,



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Date: April 24, 2006

Serial Number: 09/251,988

INFORMATIONAL DISCLOSURE CITATION (Use several sheets if necessary)				Docket Number (Optional)		Application Number		
				FIS920030301		10/928,473		
				Applicant(s)				
				Beaman, et al.				
Filing Date				Group Art Unit				
08/27/04				2833				
U.S. PATENT DOCUMENTS								
EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
LT		6,452,406	09/17/2002	Beaman, et al.				
LT		6,528,984	03/04/2003	Beaman, et al.				
U.S. PATENT APPLICATION PUBLICATIONS								
EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
FOREIGN PATENT DOCUMENTS								
	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)								
LT		US Application: 09/254/769 Title: Wafer Scale High Density Probe Assembly, Apparatus For Use Thereof And Methods Of Fabrication Thereof Filing Date: 03/11/1999 Name: Lauro, et al.						
LT		US Application: 08/756/831 Title: High Temperature Chip Test Probe Filing Date: 11/16/1996 Name: Lauro, et al.						
EXAMINER				DATE CONSIDERED				
Lorena Jones				08/28/05				
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

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SHEET 1 OF 1

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PAGE 03

PTQ/53/08A (10-01)

Schedule for form 1449WPTD		Complete if Known	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)		Application Number	10828,473
		Filing Date	August 28, 2004
		First Named Inventor	Da-Yuan Shih
		Group Art Unit	2833
		Examiner Name	Ned Yeh Assigned
		Attorney Docket Number	F18828030301US1
Sheet 1	of 1		

[illegible][illegible]

Examiner Signature	<i>Karim Hameed</i>	Date Considered	08/25/05
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* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPPEP 606. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

* Unique citation designation number. ¹ See attached *Kind of U.S. Patent Document*. ² Enter Office that issued the document, by the two-letter code (WIPO Standard 87.3). ³ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁴ Kind of document by the appropriate symbol as indicated on the document under WIPO Standard 87.46 if possible. ⁵ Applicant to place a check mark here if English language translation is attached.

Notice of References Cited	Application/Control No. 10/928,473	Applicant(s)/Patent Under Reexamination BEAMAN ET AL	
	Examiner Larisa Z. Tsukerman	Art Unit 2833	Page 1 of 2

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,356,098	03-2002	Akram et al.	324/765
	B	US-6,736,665	05-2004	Zhou et al.	439/482
	C	US-6,278,284	08-2001	Mori et al.	324/755
	D	US-6,838,097	10-2003	Wu et al.	439/482
	E	US-5,404,282	04-1995	Klinke et al.	362/249
	F	US-4,949,224	08-1990	Yamamura et al.	361/784
	G	US-6,920,689	07-2005	Khandros et al.	29/860
	H	US-4,788,498	11-1988	Maetzer et al.	324/754
	I	US-6,024,579	02-2000	Bennett, Glenn Edward	439/66
	J	US-6,255,832	07-2001	Notohardjono et al.	324/754
	K	US-6,292,003	09-2001	Fredrickson et al.	324/754
	L	US-5,399,982	03-1995	Driller et al.	324/754
	M	US-5,225,777	07-1993	Bross et al.	324/754

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	P					
	Q					
	R					
	S					
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PTO-892 (Rev. 01-2001)

Notice of References Cited

Part of Paper No. 20050802

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	Examiner Larisa Z. Tsukerman	Art Unit 2833	Page 2 of 2

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,825,422	11-2004	Eldridge et al.	174/260
	B	US-6,869,289	03-2005	Sabatier et al.	439/66
	C	US-4,863,822	10-1990	Prokopp, Manfred	324/758
	D	US-			
	E	US-			
	F	US-			
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	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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